

FORM PTO-1449	ATTY. DKT NO.	02-152-TN	PER. NO.	10/542165
	APPLICANT ADACHI et al.			
	FILING DATE	July 14, 2005	GROUP	

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
Bm		6,398,582 (Counterpart of JP-A-2000-220344; discussed on page 1 in the specification)	06/04/02	Matsuyama et al.		

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	TRANSLATION	
									NO	Eng. Abstract
Bm		JP-U-62-154762	10/01/87	JAPAN						Partial English translation
Bm		JP-A-11-243659	09/07/99	JAPAN						X

* Full English text is available in machine-translated form in JPO (Japanese Patent Office) English language web site at <http://www1.ipdl.jpo.go.jp/PA1/cgi-bin/PA1INDEX>.

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	Bm	DATE CONSIDERED	1/24/07
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FORM PTO-1449	ATTY. DKT NO.	02-152-TN	SER. NO.	10/542,165
	APPLICANT	ADACHI et al.		
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U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS

FOREIGN PATENT DOCUMENTS

									TRANSLATION	
		DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO	
										Eng. Abstract

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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

	Written Opinion issued from Japanese Patent Office issued on April 6, 2004 for the corresponding Japanese patent application No. PCT/JP2004/003174 (English translation thereof)	
	EXAMINER	DATE CONSIDERED
		1/24/07